



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: **Luu, et al.**

Serial No.: 10/765,505

Group Art Unit: 2857

Filed: 1/26/2004

Examiner: Not yet Assigned

Title: **Automated Sourcing of Substrate Microfabrication Defects Using Defect**

Signatures

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In keeping with the duty of candor and good faith owed to the Patent and Trademark Office, Applicants wish to bring the following printed publications and U.S. patent references to the attention of the Examiner.

Such references are referred to in the Background of the Specification of the Patent Application submitted herewith. Forms PTO-SB-08A and PTO-SB-08B listing these references and patent references are attached. It is understood that the Office may find additionally relevant material in these or other references.

Respectfully submitted,


DENNIS S. FERNANDEZ, ESQ.
Reg. No. 34,160

7/7/04
Date

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Name: <u>Chris Vo</u>	<u>Chris Vo</u>
Signature	Date

The Commissioner for Patents
United States Patent and Trademark Office
Alexandria, VA 22313-1450
ATTN: Mail Stop Patent Application

Re: U.S. Utility Patent Application
Appl. No. 10/765,505; Filed 1/26/2004
For: **Automated Sourcing of Substrate Microfabrication Defects Using Defect Signatures**
Inventor(s): **Luu, et al.**
Docket No.: **SPEED-P001**

Sir:

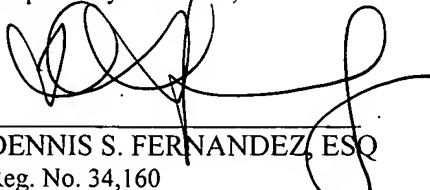
The following documents are forwarded herewith for action by the U.S. Patent and Trademark Office:

1. Information Disclosure Statement;
2. Form PTO/SB/08A with 4 U.S. References;
3. Form PTO/SB/08B with 10 Non Patent Literature Documents; and
4. A return post card.

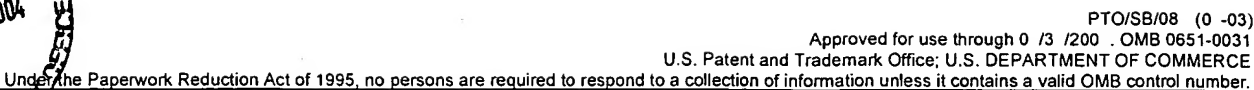
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717104
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Respectfully submitted,


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Complete if Known

(Use as many sheets as necessary)

Sheet	1	of	2
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Application Number	10/765,505
Filing Date	1/26/2004
First Named Inventor	Luu, et al.
Art Unit	2857
Examiner Name	Not Yet Assigned
Attorney Docket Number	SPEED-P001

[illegible][illegible]

Examiner
Signature

Date
Considered

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Application Number	10/765,505
Filing Date	1/26/2004
First Named Inventor	Luu, et al.
Art Unit	2857
Examiner Name	Not Yet Assigned
Attorney Docket Number	SPEED-P001

Sheet 2 of 2

ON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	1	TOBIN, et al., Feature Analysis and Classification of Manufacturing Signatures Based on Semiconductor Wafermaps 12 pages.	
	2	TOBIN, et al., Automatic Classification of Spatial Signatures on Semiconductor Wafermaps 11 pages.	
	3	KARNOWSKI, et al., Fuzzy Logic Connectivity in Semiconductor Defect Clustering 10 pages.	
	4	GLEASON, et al., An Integrated Spatial Signature Analysis and Automatic Defect Classification System 8 pages.	
	5	GLEASON, et al., Rapid Yield Learning though Optical Defect and Electrical Test Analysis 11 pages.	
	6	TOBIN, et al., An Image Paradigm for Semiconductor Defect Data Reduction 12 pages.	
	7	TOBIN, et al., Automated Analysis for Rapid Defect Sourcing and Yeild Learning 15 pages.	
	8	TOBIN, et al., Using Historical Wafermap Data for Automated Yeild Analysis 16 pages.	
	9	TOBIN, et al., Adaptation of The Fuzzy K-Nearest Neighbor Classifier for Manufacturing Automation 9 pages.	
	10	TOBIN, et al., Image Retrieval in the Industrial Environment 9 pages.	

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